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Application/Control No.	Applicant(s)/Patent under Reexamination
10/647,224	SEKI, HIROSHI
Examiner	Art Unit
Joseph Chang	2817

	SEARCHED		
Class	Subclass	Date	Examiner
331	108A,158 116FE,	2/9/2005	JC
331	116R,160		
331	107A,108d		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			:

SEAR((INCLUDING SE	CH NOTE	ES TRATEGY)
		DATE	EXMR
EAST(attached)		2/9/2005	JC